

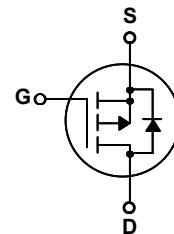
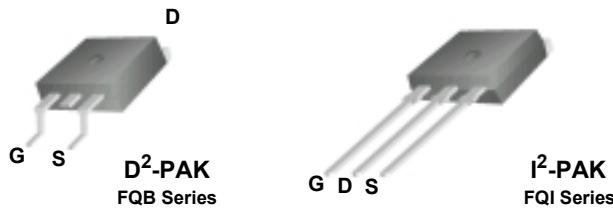
FQB1P50 / FQI1P50 500V P-Channel MOSFET

General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology. This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for electronic lamp ballasts based on the complementary half bridge topology.

Features

- 1.5A, -500V, $R_{DS(on)} = 10.5\Omega$ @ $V_{GS} = -10$ V
- Low gate charge (typical 11 nC)
- Low C_{SS} (typical 6.0 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS Compliant



Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FQB1P50 / FQI1P50	Units
V_{DSS}	Drain-Source Voltage	-500	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	-1.5	A
	- Continuous ($T_C = 100^\circ\text{C}$)	-0.95	A
I_{DM}	Drain Current - Pulsed	(Note 1)	A
V_{GSS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	mJ
I_{AR}	Avalanche Current	(Note 1)	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	V/ns
P_D	Power Dissipation ($T_A = 25^\circ\text{C}$) *	3.13	W
	Power Dissipation ($T_C = 25^\circ\text{C}$)	63	W
	- Derate above 25°C	0.51	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	1.98	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *	--	40	$^\circ\text{C}/\text{W}$
$R_{\theta CA}$	Thermal Resistance, Case-to-Ambient	--	62.5	$^\circ\text{C}/\text{W}$

* When mounted on the minimum pad size recommended (PCB Mount)

Electrical Characteristics						
$T_C = 25^\circ\text{C}$ unless otherwise noted						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$, $I_D = -250 \mu\text{A}$	-400	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C	--	-	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -500 \text{ V}$, $V_{GS} = 0 \text{ V}$	--	--	-1	μA
		$V_{DS} = -400 \text{ V}$, $T_C = 125^\circ\text{C}$	--	--	-10	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = -30 \text{ V}$, $V_{DS} = 0 \text{ V}$	--	--	-100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$	--	--	100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = -250 \mu\text{A}$	-3.0	--	-5.0	V
$R_{DS(\text{on})}$	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}$, $I_D = -0.75 \text{ A}$	--	8.0	10.5	Ω
g_{FS}	Forward Transconductance	$V_{DS} = -50 \text{ V}$, $I_D = -0.75 \text{ A}$ (Note 4)	--	1.26	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$	--	270	350	pF
C_{oss}	Output Capacitance		--	40	50	pF
C_{rss}	Reverse Transfer Capacitance		--	6.0	8.0	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = -250 \text{ V}$, $I_D = -1.5 \text{ A}$, $R_G = 25 \Omega$	--	9.0	30	ns
t_r	Turn-On Rise Time		--	25	60	ns
$t_{d(off)}$	Turn-Off Delay Time		--	27	65	ns
t_f	Turn-Off Fall Time		--	30	70	ns
Q_g	Total Gate Charge	$V_{DS} = -400 \text{ V}$, $I_D = -1.5 \text{ A}$, $V_{GS} = -10 \text{ V}$	--	11	14	nC
Q_{gs}	Gate-Source Charge		--	2.0	--	nC
Q_{gd}	Gate-Drain Charge		--	5.6	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	-1.5	--	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	-6.0	--	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}$, $I_S = -1.5 \text{ A}$	--	--	-5.0	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}$, $I_S = -1.5 \text{ A}$, $dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	200	--	ns
Q_{rr}	Reverse Recovery Charge		--	0.7	--	μC

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 88\text{mH}$, $I_{AS} = -1.5\text{A}$, $V_{DD} = -50\text{V}$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq -1.5\text{A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Characteristics

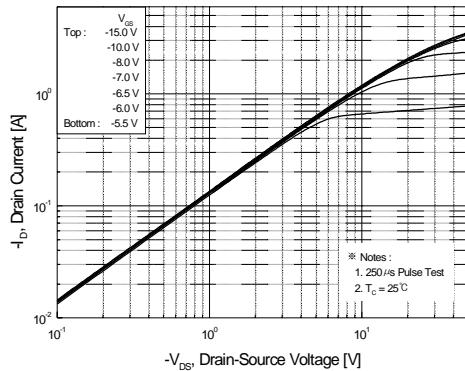


Figure 1. On-Region Characteristics

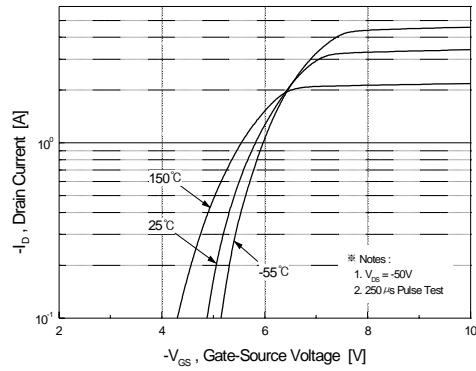


Figure 2. Transfer Characteristics

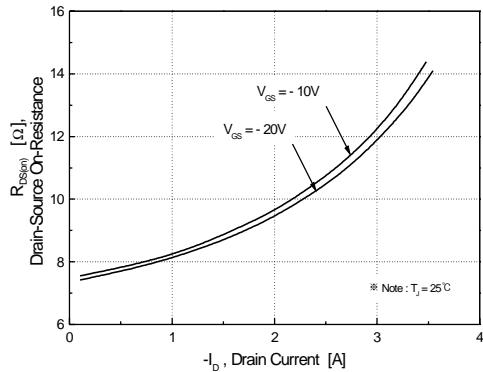


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

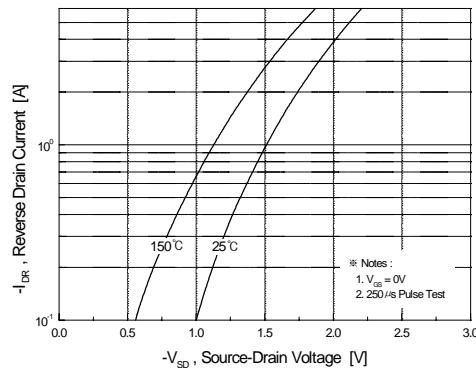


Figure 4. Body Diode Forward Voltage
Variation vs. Source Current
and Temperature

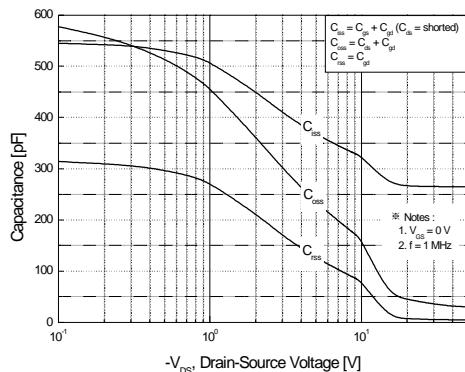


Figure 5. Capacitance Characteristics

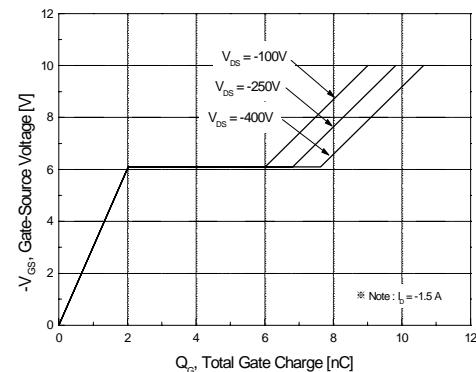


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

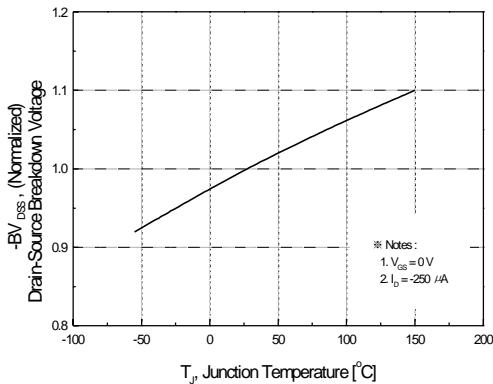


Figure 7. Breakdown Voltage Variation vs. Temperature

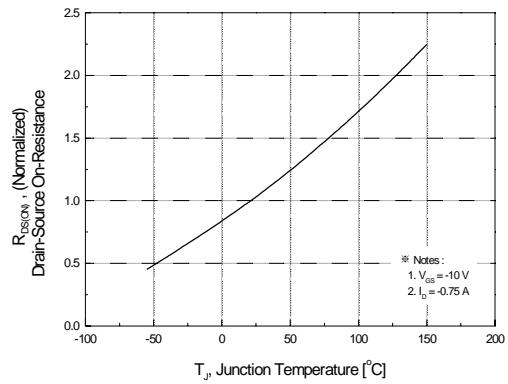


Figure 8. On-Resistance Variation vs. Temperature

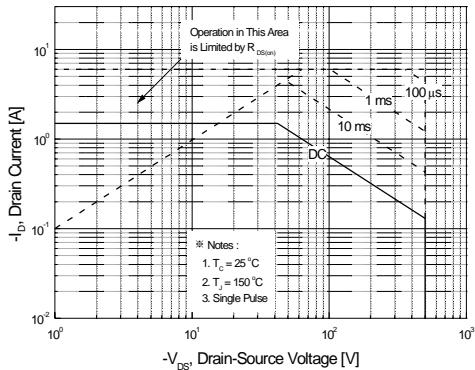


Figure 9. Maximum Safe Operating Area

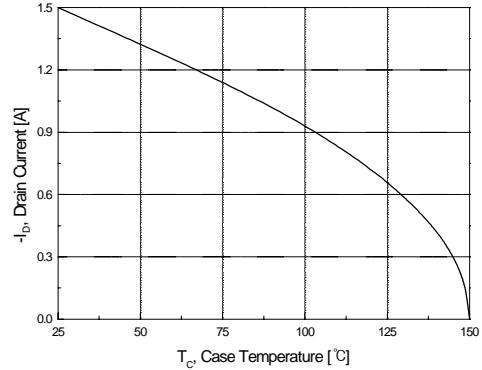


Figure 10. Maximum Drain Current vs. Case Temperature

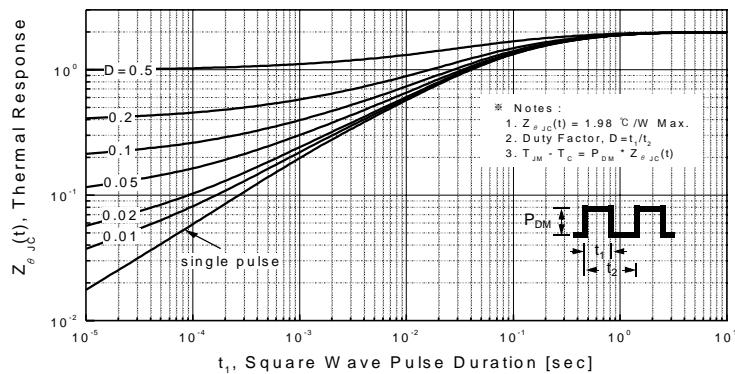
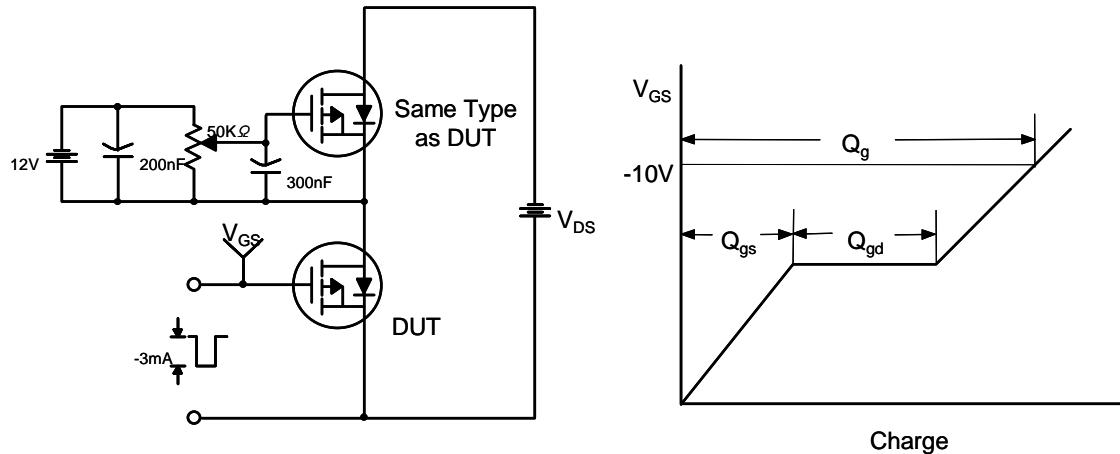
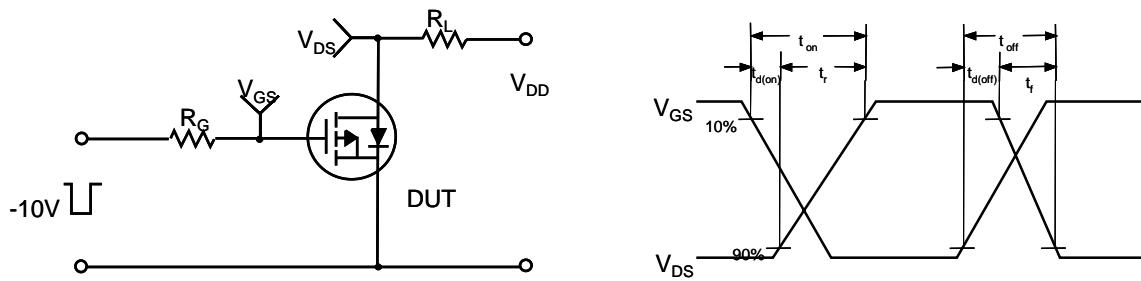


Figure 11. Transient Thermal Response Curve

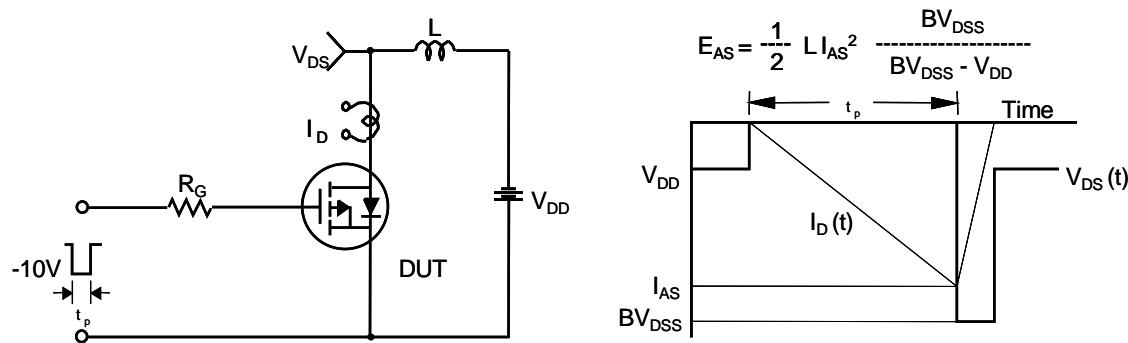
Gate Charge Test Circuit & Waveform



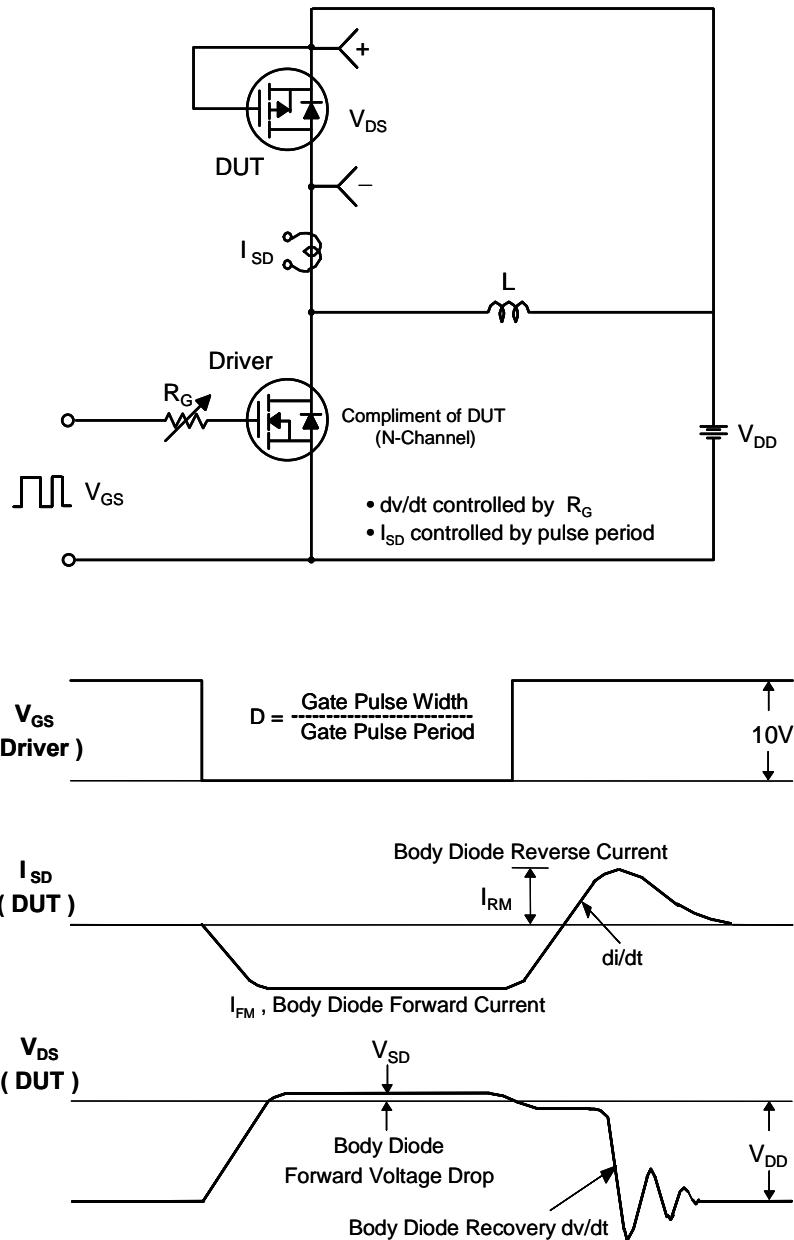
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

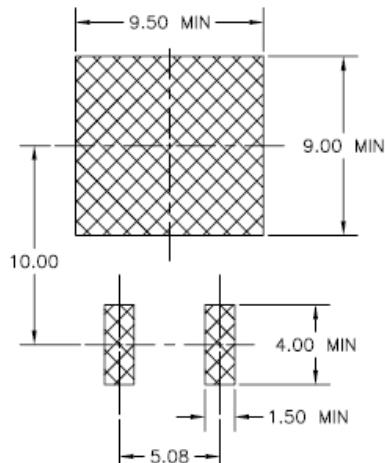
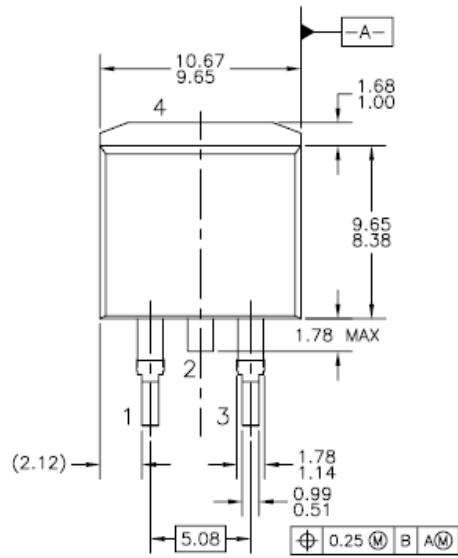


Peak Diode Recovery dv/dt Test Circuit & Waveforms

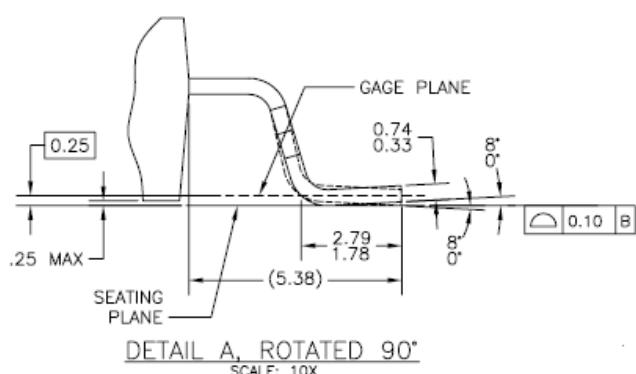
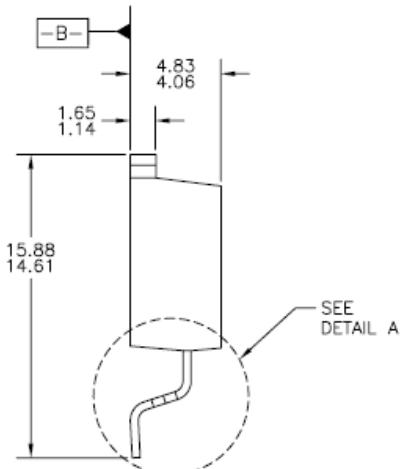
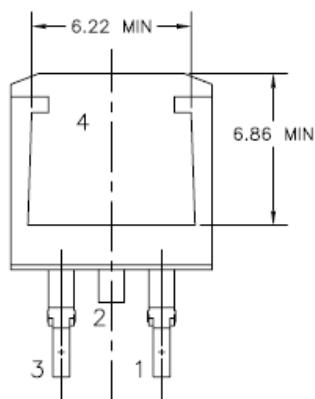


Package Dimensions

D² - PAK



LAND PATTERN RECOMMENDATION

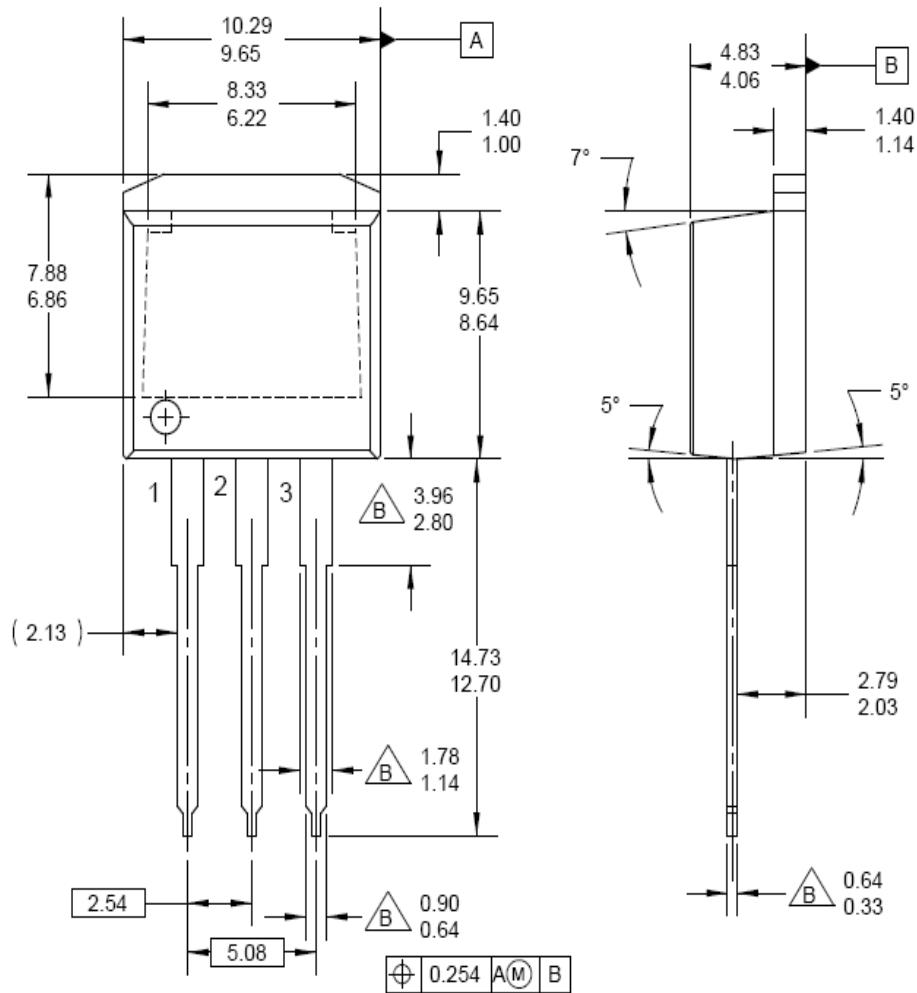


DETAIL A, ROTATED 90°
SCALE: 10X

Dimensions in Millimeters

Package Dimensions (Continued)

I² - PAK



Dimensions in Millimeters



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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
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